

In the Specification

At page 1, before the "Technical Field" insert:

CROSS REFERENCE TO RELATED APPLICATION

This patent resulted from and claims priority to divisional U.S. Patent Application Serial No. 10/232,295, filed August 30, 2002, entitled "Method and Apparatus for Testing Semiconductor Circuitry for Operability and Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability," naming Warren F. Farnworth et al. as inventors, which is a divisional of U.S. Patent Application Serial No. 10/057,711, filed January 22, 2002, now U.S. Patent No. 6,670,819, which is a divisional of U.S. Patent Application Serial No. 09/411,139, filed October 1, 1999; now U.S. Patent No. 6,657,450, which is a divisional application of U.S. Patent Application Serial No. 09/267,990, filed March 12, 1999, now U.S. Patent No. 6,380,754, which is a divisional application of U.S. Patent Application Serial No. 08/895,764, filed July 17, 1997, now U.S. Patent No. 6,127,195, which is a continuation of U.S. Patent Application Serial No. 08/621,157, filed March 21, 1996, since abandoned; which is a continuation of U. S. Patent Application Serial No. 08/206,747, filed March 4, 1994, now U. S. Patent No. 5,523,697, which is a divisional of U. S. Patent Application Serial No. 08/116,394, filed September 3, 1993, now U. S. Patent No. 5,326,428, the disclosures of which are incorporated by reference.